

**Search Notes**

Application/Control No.

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Examiner

Vivian Chen

Applicant(s)/Patent under  
Reexamination

TAKEI ET AL.

Art Unit

1773

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
interference search printout		9/16/2005	VC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (search history printout)	9/16/2005	VC
inventor search	9/16/2005	VC